

<b>Issue Classification</b>		<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
		10/613,316	CHEN, WEI-ZEN
		Examiner	Art Unit
		Joseph Chang	2817

ISSUE CLASSIFICATION			
ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
331	45	331	2
INTERNATIONAL CLASSIFICATION		327	147
H	0	L	7/06
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/			
Joseph Chang (Assistant Examiner) (Date) <i>Chang 2/23/05</i> (Legal Instruments Examiner) (Date)		BENNY LEE PRIMARY EXAMINER ART UNIT 2817 <i>Benny Lee</i> (Primary Examiner)	Total Claims Allowed: 3 18 Feb 2005 (Date)
		O.G. Print Claim(s)	O.G. Print Fig.
		1	2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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9		38	68	98	128	158	188
10		39	69	99	129	159	189
11		40	70	100	130	160	190
12		41	71	101	131	161	191
13		42	72	102	132	162	192
14		43	73	103	133	163	193
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